

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		10/790,728	HAN, CHEUL KYUNG	
Examiner Linh T. Nguyen		Art Unit 2627	Page 1 of 1	

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0161237	08-2003	Ogawa, Toshihiro	369/47.53
*	B	US-7,095,691	08-2006	Takeda, Naoto	369/47.53
*	C	US-2005/0122868	06-2005	Kim, Jeong Woo	369/047.53
*	D	US-2002/0064110	05-2002	Sato, Shinichi	369/47.53
*	E	US-2002/0024903	02-2002	Sato, Shinichi	369/47.53
*	F	US-2002/0126603	09-2002	Kim, Joo-youp	369/47.53
*	G	US-2004/0141442	07-2004	Suzuki, Haruyuki	369/047.53
*	H	US-2005/0157620	07-2005	Narumi et al.	369/047.53
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.